

ABSTRACT

Automatic test equipment for testing a plurality of devices-under-test is disclosed. The equipment includes a plurality of channel modules, each of the channel modules having a plurality of channels with each channel corresponding to a pin of one of the devices-under-test. Programmable delay circuitry is coupled to each
5 channel module. The programmable delay circuitry includes a deskew circuit adapted to be shared by more than one of the channels of the coupled channel module.